Module Description

Module name	Material Characterization Techniques
Module level, if applicable	Bachelor of Physics
Code, if applicable	18H02131703
Subtitle, if applicable	-
Course, if applicable	-
Semester(s) in which the module is taught	5 th
Person responsible for the module	Prof. Dr. Dahlang Tahir, M.Si.
Lecturer	 Prof. Dr. Dahlang Tahir, M. Si. Prof. Dr. Paulus Lobo Gareso, M. Sc. Heryanto, S. Si, M. Si.
Language	Indonesian Language [Bahasa Indonesia]
Relation to Curriculum	Undergraduate degree program, elective, 5 th semester
Type of teaching, contact hours	Teaching methods: [group discussion], [problem-based learning]. Teaching forms: [lecture], [tutorial]. CH: 08.00 - 16.00
Workload	For this course, students are required to meet a minimum of 136.00 hours in one semester, which consist of: - 40.00 hours for lecture, - 48.00 hours for structured assignments, - 48.00 hours for private study
Credit points	3 credit points (equivalent with 5.1 ECTS)

Requirements according to the examination regulations	A student must have attended at least 75% of the lectures to sit in the exams
Recommended prerequisites	Solid Matter Physics
Module objectives/intended learning outcomes	 After completing the course, Students are able: Intended Learning Outcomes (ILO): ILO 1: Students have a relatively deep understanding in classical and basic quantum physics. [ILO 1 - Kn] ILO 3: Students are able to use the basic principles of physics in technology application. [ILO 3 - Kn] ILO 4: Students have capability to operate the physical instrumentation in the laboratory and conduct experiments and interpret the result. [ILO 4 - Ab] Course Learning Objective (CLO): After completing this course, students are expected to be able to: Explain the concept of material physics which includes the definition of artificial radiation sources, radiation characteristics, and the process of interaction of radiation with materials. Explain the types of electromagnetic wave interactions in materials and their mechanisms. Determine the properties of the material based on the results of diffraction, absorption and transmission of electromagnetic waves in the test sample. Explain the use of characterization tools and analyze the data obtained. Sub CLO: ECLO 1: Explain the meaning of artificial radiation sources and utilization and characteristics of radiation. ILO 4 ⇒ CLO 2: Describe the interaction of electromagnetic waves on the material. ILO 4 ⇒ CLO 3: Explain the type of electromagnetic wave interaction mechanism on the test sample. ILO 4 ⇒ CLO 4: Describe the properties of materials such as structure, bonding, and morphology.

	 ILO 4 ⇒ CLO 5: Explain the results of data processing from the results of the characterization. ILO 3 ⇒ CLO 6: Describes how to extract data derived from characterization tools. ILO 3 ⇒ CLO 7: Explain the use of tools based on their working principles.
Content	Students will learn about: 1. Artificial Radiation 2. Characteristics of Radiation 3. Interaction of Radiation with Materials 4. Mechanism of electromagnetic waves with materials 5. Data extraction and data processing tools (XRD, FTIR, XRF, VNA and SEM) 6. Determine material properties based on characterization data 7. Material characterization tools
Forms of Assessment	Assessment techniques: [performance], [written test]. Assessment forms: [assignment], [presentation], [midterm exam], [final term exam]. Assignment = 33%, Presentation = 15%, Mid term exam = 25% Final term exam = 27% CLO 1 => ILO 1: 16% (8% Assignment 1 number 1-2, 8% MID exam number 1) CLO 2 => ILO 4: 16% (8% Assignment 1 number 3-4, 8% MID exam number 2) CLO 3 => ILO 4: 17% (8% Assignment 2 number 1-2, 9% MID exam number 3) CLO 4 => ILO 4: 8% (8% Assignment 2 number 3) CLO 5 => ILO 4: 16% (8% Presentation 1, 8% Final term exam number 1) CLO 6 => ILO 3: 17% (8% Presentation 2, 9% Final term exam number 2) CLO 7 => ILO 3: 10% (10% Final term exam number 3)
Study and examination requirements and	Study and examination requirements: - Students must attend 15 minutes before the class starts Students must switch off all electronic devices.

forms of examination	 Students must inform the lecturer if they will not attend the class due to sickness, etc. Students must submit all class assignments before the deadline. Students must attend the exam to get a final grade. Form of examination: Written exam: Essay
Media employed	Software (Origin, MATLAB, MATCH), Hardware (LCD and White Board), Learning Management System (SIKOLA).
Reading list	 Agus setia budi dkk., 2012, Karakterisasi Material: Prinsip dan aplikasinya, edisi pertama, UPI Pres, Bandung. William D. Callister, Jr., 2007, Materials Science and Engineering, seventh edition, Jhon Wiley and Son, inc, Utah University. B Cullity, 1956, elementary X-Ray Diffraction, Addison-Wesley company, United state of America. Support: A. Khorsand Zak et al., X-ray analysis of ZnO nanoparticles by Williamson Hall and size strain plot methods Solid State Sciences 13 (2011) 251-256. Suryani, et al. Quantitative analysis of diffraction and infra-red spectra of composite cement/BaSO4/Fe3O4for determining correlation between attenuation coefficient, structural and optical properties Ceramic International 46 (2020) 18601-18607. K. Yasui, et al., Three-dimensional structure recognition of circuit patterns on semiconductor devices using multiple SEM images detected in different electron scattering angles Microelectronics Reliability 108 (2020) 113628. Pustaka lainnya dari internet.